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"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

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Details

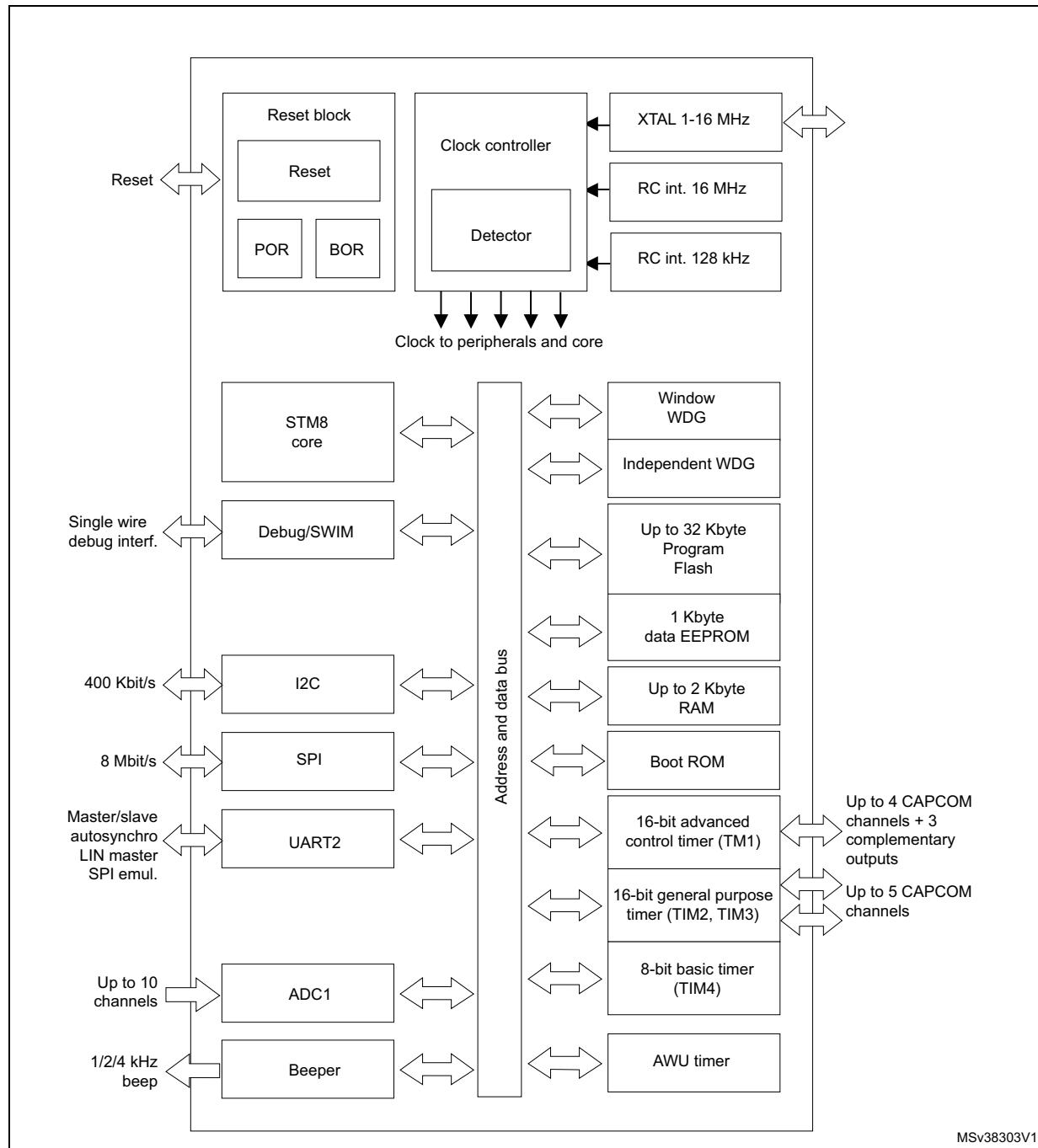
Product Status	Active
Core Processor	STM8A
Core Size	8-Bit
Speed	16MHz
Connectivity	I ² C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	25
Program Memory Size	16KB (16K x 8)
Program Memory Type	FLASH
EEPROM Size	1K x 8
RAM Size	2K x 8
Voltage - Supply (Vcc/Vdd)	2.95V ~ 5.5V
Data Converters	A/D 7x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-UFQFPN (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8s105k4u3atr

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3 Block diagram

Figure 1. STM8S105x4/6 block diagram



4.12 TIM4 - 8-bit basic timer

- 8-bit auto reload, adjustable prescaler ratio to any power of 2 from 1 to 128
- Clock source: CPU clock
- Interrupt source: 1 x overflow/update

Table 3. TIM timer features

Timer	Counter size (bits)	Prescaler	Counting mode	CAPCOM channels	Complementary outputs	Ext. trigger	Timer synchronization/chaining
TIM1	16	Any integer from 1 to 65536	Up/down	4	3	Yes	No
TIM2	16	Any power of 2 from 1 to 32768	Up	3	0	No	
TIM3	16	Any power of 2 from 1 to 32768	Up	2	0	No	
TIM4	8	Any power of 2 from 1 to 128	Up	0	0	No	

4.13 Analog-to-digital converter (ADC1)

The STM8S105x4/6 products contain a 10-bit successive approximation A/D converter (ADC1) with up to 10 multiplexed input channels and the following main features:

- Input voltage range: 0 to VDD
- Conversion time: 14 clock cycles
- Single and continuous and buffered continuous conversion modes
- Buffer size ($n \times 10$ bits) where n = number of input channels
- Scan mode for single and continuous conversion of a sequence of channels
- Analog watchdog capability with programmable upper and lower thresholds
- Analog watchdog interrupt
- External trigger input
- Trigger from TIM1 TRGO
- End of conversion (EOC) interrupt

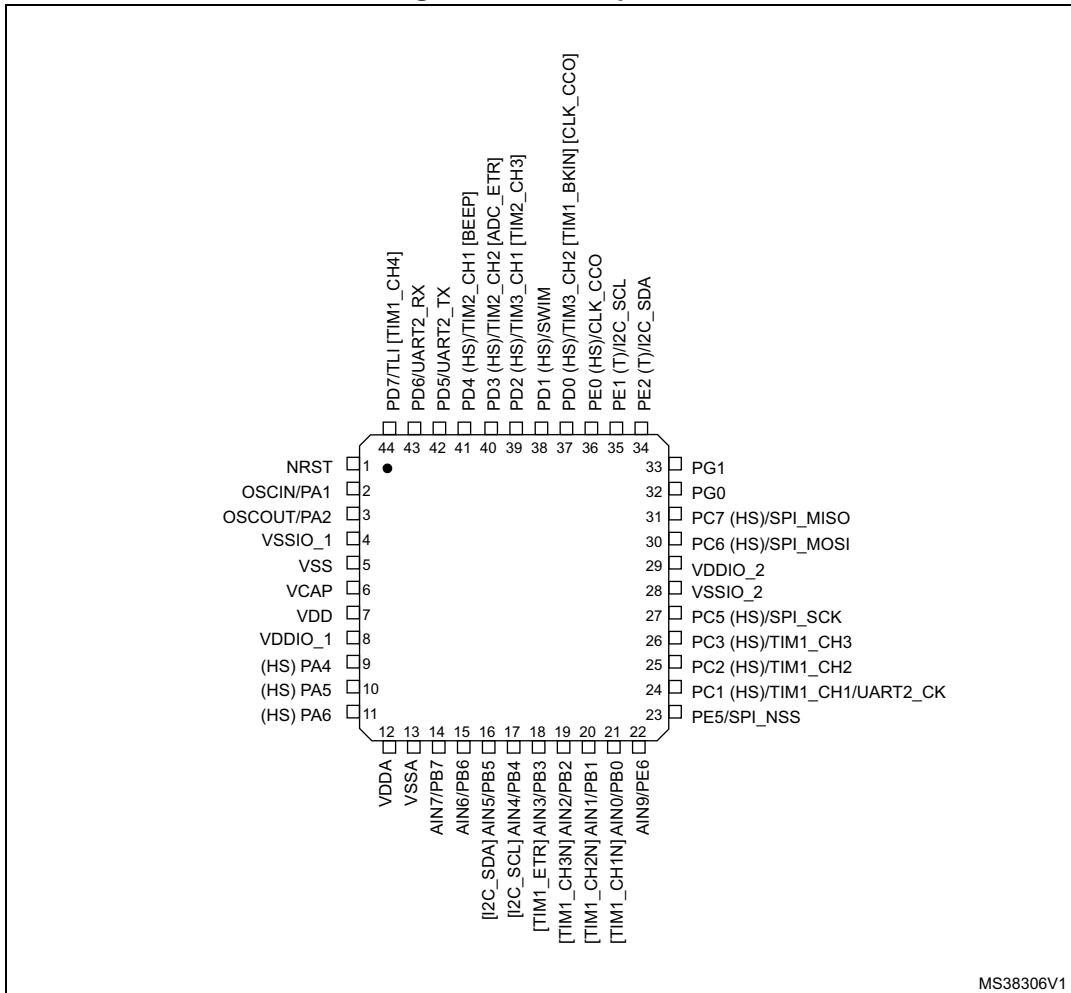
Note: Additional AIN12 analog input is not selectable in ADC scan mode or with analog watchdog. Values converted from AIN12 are stored only into the ADC_DRH/ADC_DRL registers.

5 Pinout and pin description

Table 4. Legend/abbreviations for pin description tables

Type	I= Input, O = Output, S = Power supply	
Level	Input	CM = CMOS
	Output	HS = High sink
Output speed	O1 = Slow (up to 2 MHz) O2 = Fast (up to 10 MHz) O3 = Fast/slow programmability with slow as default state after reset O4 = Fast/slow programmability with fast as default state after reset	
Port and control configuration	Input	float = floating, wpu = weak pull-up
	Output	T = True open drain, OD = Open drain, PP = Push pull
Reset state	Bold X (pin state after internal reset release). Unless otherwise specified, the pin state is the same during the reset phase and after the internal reset release.	

Figure 4. LQFP44 pinout



1. (HS) high sink capability.
2. (T) True open drain (P-buffer and protection diode to V_{DD} not implemented).
3. [] alternate function remapping option (if the same alternate function is shown twice, it indicates an exclusive choice not a duplication of the function).

Table 5. STM8S105x4/6 pin description (continued)

Pin number				Pin name	Type	Input			Output			Main function (after reset)	Default alternate function	Alternate function after remap [option bit]	
LQFP48	LQFP44	LQFP32/UFBFPN32	SDIP32			Floating	wpu	Ext. interrupt	High sink	Speed	OD	PP			
40	36	-	-	PE0/ CLK_CCO	I/O	X	X	X	HS	O3	X	X	Port E0	Configurable clock output	-
41	37	25	30	PD0/ TIM3_CH2 [TIM1_BKIN] [CLK_CCO]	I/O	X	X	X	HS	O3	X	X	Port D0	Timer 3 - channel 2	TIM1_BKIN [AFR3]/ CLK_CC0 [AFR2]
42	38	26	31	PD1/ SWIM ⁽⁵⁾	I/O	X	X	X	X	HS	O4	X	Port D1	SWIM data interface	-
43	39	27	32	PD2/ TIM3_CH1 [TIM2_CH3]	I/O	X	X	X	HS	O3	X	X	Port D2	Timer 3 - channel 1	TIM2_CH3 [AFR1]
44	40	28	1	PD3/ TIM2_CH2 [ADC_ETR]	I/O	X	X	X	HS	O3	X	X	Port D3	Timer 2 - channel 2	ADC_ETR [AFR0]
45	41	29	2	PD4/ TIM2_CH1 [BEEP]	I/O	X	X	X	HS	O3	X	X	Port D4	Timer 2 - channel 1	BEEP output [AFR7]
46	42	30	3	PD5/ UART2_TX	I/O	X	X	X	-	O1	X	X	Port D5	UART2 data transmit	-
47	43	31	4	PD6/ UART2_RX	I/O	X	X	X	-	O1	X	X	Port D6	UART2 data receive	-
48	44	32	5	PD7/ TLI [TIM1_CH4]	I/O	X	X	X	-	O1	X	X	Port D7	Top level interrupt	TIM1_CH4 [AFR4]

1. A pull-up is applied to PF4 during the reset phase. This pin is input floating after reset release.
2. AIN12 is not selectable in ADC scan mode or with analog watchdog.
3. In 44-pin package, AIN9 cannot be used by ADC scan mode.
4. In the open-drain output column, 'T' defines a true open-drain I/O (P-buffer, weak pull-up and protection diode to V_{DD} are not implemented).
5. The PD1 pin is in input pull-up during the reset phase and after internal reset release.

6.2.2 General hardware register map

Table 8. General hardware register map

Address	Block	Register label	Register name	Reset status
0x00 5050 to 0x00 5059	Reserved area (10 byte)			
0x00 505A	Flash	FLASH_CR1	Flash control register 1	0x00
0x00 505B		FLASH_CR2	Flash control register 2	0x00
0x00 505C		FLASH_NCR2	Flash complementary control register 2	0xFF
0x00 505D		FLASH_FPR	Flash protection register	0x00
0x00 505E		FLASH_NFPR	Flash complementary protection register	0xFF
0x00 505F		FLASH_IAPSR	Flash in-application programming status register	0x00
0x00 5060 to 0x00 5061	Reserved area (2 byte)			
0x00 5062	Flash	FLASH_PUKR	Flash program memory unprotection register	0x00
0x00 5063	Reserved area (1 byte)			
0x00 5064	Flash	FLASH_DUKR	Data EEPROM unprotection register	0x00
0x00 5065 to 0x00 509F	Reserved area (59 byte)			
0x00 50A0	ITC	EXTI_CR1	External interrupt control register 1	0x00
0x00 50A1		EXTI_CR2	External interrupt control register 2	0x00
0x00 50A2 to 0x00 50B2	Reserved area (17 byte)			
0x00 50B3	RST	RST_SR	Reset status register	0XX ⁽¹⁾
0x00 50B4 to 0x00 50BF	Reserved area (12 byte)			
0x00 50C0	CLK	CLK_ICKR	Internal clock control register	0x01
0x00 50C1		CLK_ECKR	External clock control register	0x00
0x00 50C2	Reserved area (1 byte)			

7 Interrupt vector mapping

Table 10. Interrupt mapping

IRQ no.	Source block	Description	Wakeup from halt mode	Wakeup from active-halt mode	Vector address
-	RESET	Reset	Yes	Yes	0x00 8000
-	TRAP	Software interrupt	-	-	0x00 8004
0	TLI	External top level interrupt	-	-	0x00 8008
1	AWU	Auto wake up from halt	-	Yes	0x00 800C
2	CLK	Clock controller	-	-	0x00 8010
3	EXTI0	Port A external interrupts	Yes ⁽¹⁾	Yes ⁽¹⁾	0x00 8014
4	EXTI1	Port B external interrupts	Yes	Yes	0x00 8018
5	EXTI2	Port C external interrupts	Yes	Yes	0x00 801C
6	EXTI3	Port D external interrupts	Yes	Yes	0x00 8020
7	EXTI4	Port E external interrupts	Yes	Yes	0x00 8024
8	Reserved	-	-	-	0x00 8028
9	Reserved	-	-	-	0x00 802C
10	SPI	End of transfer	Yes	Yes	0x00 8030
11	TIM1	TIM1 update/ overflow/ underflow/ trigger/ break	-	-	0x00 8034
12	TIM1	TIM1 capture/ compare	-	-	0x00 8038
13	TIM2	TIM2 update/ overflow	-	-	0x00 803C
14	TIM2	TIM2 capture/ compare	-	-	0x00 8040
15	TIM3	TIM3 update/ overflow	-	-	0x00 8044
16	TIM3	TIM3 capture/ compare	-	-	0x00 8048
17	Reserved	-	-	-	0x00 804C
18	Reserved	-	-	-	0x00 8050
19	I2C	I2C interrupt	Yes	Yes	0x00 8054

Table 10. Interrupt mapping (continued)

IRQ no.	Source block	Description	Wakeup from halt mode	Wakeup from active-halt mode	Vector address
20	UART2	Tx complete	-	-	0x00 8058
21	UART2	Receive register DATA FULL	-	-	0x00 805C
22	ADC1	ADC1 end of conversion/ analog watchdog interrupt	-	-	0x00 8060
23	TIM4	TIM4 update/ overflow	-	-	0x00 8064
24	Flash	EOP/WR_PG_DIS	-	-	0x00 8068
Reserved					0x00 806C to 0x00 807C

1. Except PA1.

Table 12. Option byte description (continued)

Option byte no.	Description
OPT4	EXTCLK: External clock selection 0: External crystal connected to OSCIN/OSCOUT 1: External clock signal on OSCIN
	CKAWUSEL: Auto wake-up unit/clock 0: LSI clock source selected for AWU 1: HSE clock with prescaler selected as clock source for AWU
	PRSC[1:0] AWU clock prescaler 0x: 16 MHz to 128 kHz prescaler 10: 8 MHz to 128 kHz prescaler 11: 4 MHz to 128 kHz prescaler
OPT5	HSECNT[7:0]: HSE crystal oscillator stabilization time 0x00: 2048 HSE cycles 0xB4: 128 HSE cycles 0xD2: 8 HSE cycles 0xE1: 0.5 HSE cycles
OPT6	Reserved
OPT7	Reserved
OPTBL	BL[7:0]: Bootloader option byte For STM8S products, this option is checked by the boot ROM code after reset. Depending on the content of addresses 0x487E, 0x487F, and 0x8000 (reset vector), the CPU jumps to the bootloader or to the reset vector. Refer to the UM0560 (STM8L/S bootloader manual) for more details. For STM8L products, the bootloader option bytes are on addresses 0xFFFF and 0xFFFF+1 (2 byte). These option bytes control whether the bootloader is active or not. For more details, refer to the UM0560 (STM8L/S bootloader manual) for more details.

10 Electrical characteristics

10.1 Parameter conditions

Unless otherwise specified, all voltages are referred to V_{SS} .

10.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at $T_A = 25^\circ\text{C}$, and $T_A = T_{A\text{max}}$ (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation (mean $\pm 3 \Sigma$).

10.1.2 Typical values

Unless otherwise specified, typical data are based on $T_A = 25^\circ\text{C}$, $V_{DD} = 5.0\text{ V}$. They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated (mean $\pm 2 \Sigma$).

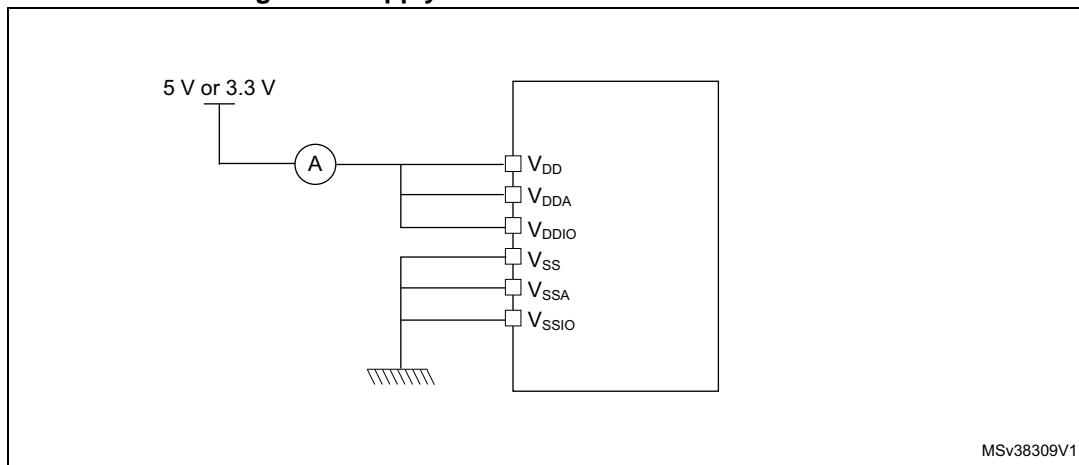
10.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

10.1.4 Typical current consumption

For typical current consumption measurements, V_{DD} , V_{DDIO} and V_{DDA} are connected together in the configuration shown in the following figure.

Figure 8. Supply current measurement conditions



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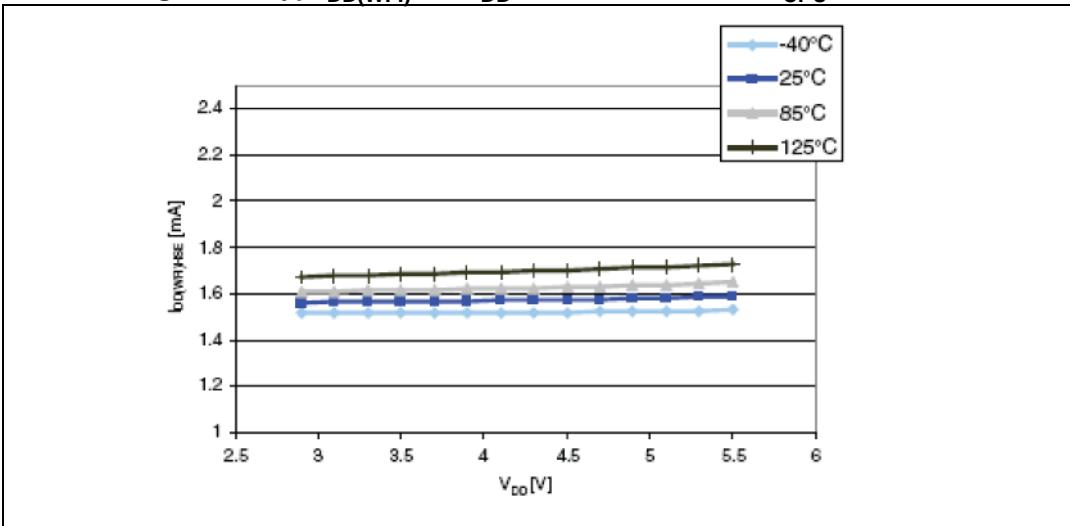
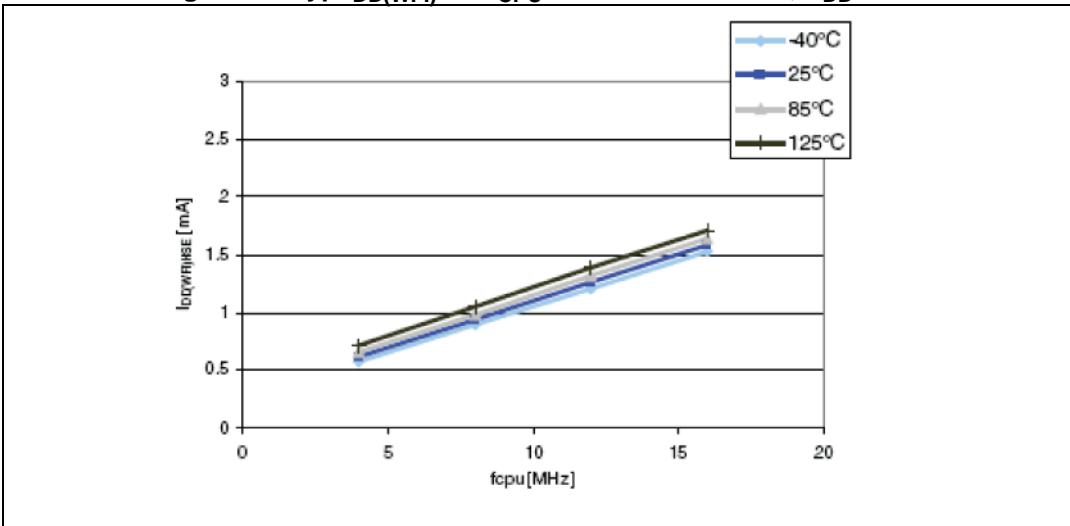
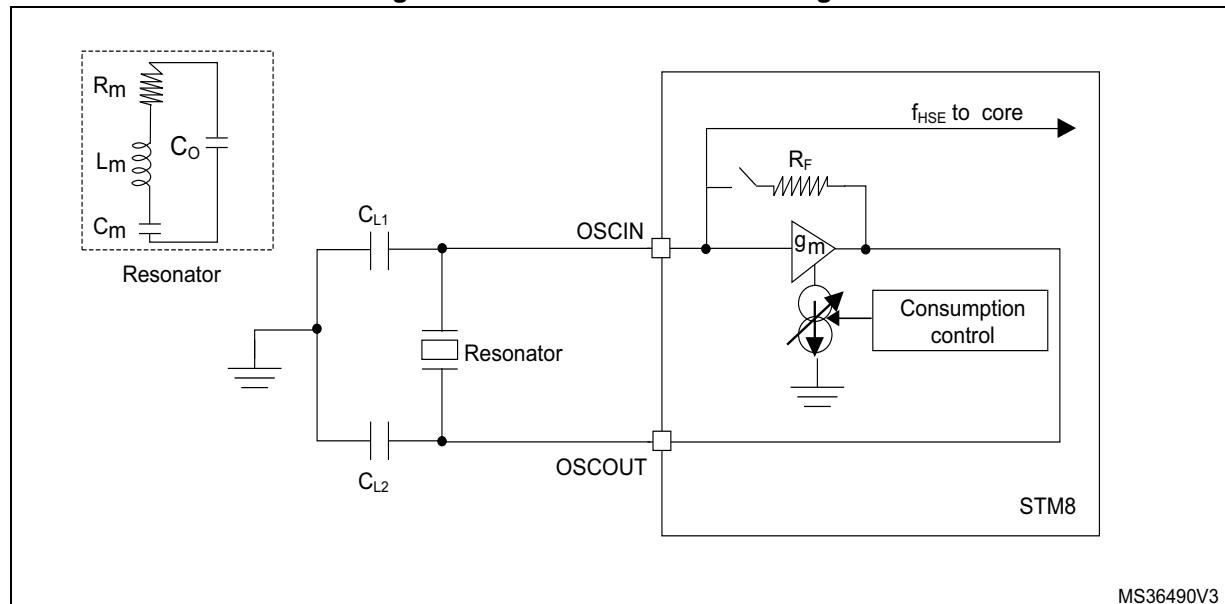
Figure 16. Typ $I_{DD(WFI)}$ vs. V_{DD} HSE external clock, $f_{CPU} = 16$ MHz**Figure 17. Typ $I_{DD(WFI)}$ vs. f_{CPU} HSE external clock, $V_{DD} = 5$ V**

Figure 20. HSE oscillator circuit diagram



MS36490V3

HSE oscillator critical g_m equation

$$g_{m\text{crit}} = (2 \times \pi \times f_{HSE})^2 \times R_m(2C_0 + C)^2$$

R_m : Notional resistance (see crystal specification)

L_m : Notional inductance (see crystal specification)

C_m : Notional capacitance (see crystal specification)

C_0 : Shunt capacitance (see crystal specification)

$C_{L1} = C_{L2} = C$: Grounded external capacitance

$g_m \gg g_{m\text{crit}}$

10.3.6 I/O port pin characteristics

General characteristics

Subject to general operating conditions for V_{DD} and T_A unless otherwise specified. All unused pins must be kept at a fixed voltage, using the output mode of the I/O for example or an external pull-up or pull-down resistor.

Table 37. I/O static characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IL}	Input low level voltage	$V_{DD} = 5\text{ V}$	-0.3 V	-	$0.3 \times V_{DD}$	V
V_{IH}	Input high level voltage		$0.7 \times V_{DD}$	-	$V_{DD} + 0.3\text{ V}$	
V_{hys}	Hysteresis ⁽¹⁾		-	700	-	mV
R_{pu}	Pull-up resistor	$V_{DD} = 5\text{ V}$, $V_{IN} = V_{SS}$	30	55	80	k Ω
t_R , t_F	Rise and fall time (10% - 90%)	Fast I/Os Load = 50 pF	-	-	35 ⁽²⁾	ns
		Standard and high sink I/Os Load = 50 pF	-	-	125 ⁽²⁾	
t_R , t_F	Rise and fall time (10% - 90%)	Fast I/Os Load = 20 pF	-	-	20 ⁽²⁾	ns
		Standard and high sink I/Os Load = 20 pF	-	-	50 ⁽²⁾	
I_{Ikg}	Digital input leakage current	$V_{SS} \leq V_{IN} \leq V_{DD}$	-	-	$\pm 1^{(3)}$	μA
$I_{Ikg\ ana}$	Analog input leakage current	$V_{SS} \leq V_{IN} \leq V_{DD}$	-	-	$\pm 250^{(3)}$	nA
$I_{Ikg(inj)}$	Leakage current in adjacent I/O	Injection current $\pm 4\text{ mA}$	-	-	$\pm 1^{(3)}$	μA

1. Hysteresis voltage between Schmitt trigger switching levels. Based on characterization results, not tested in production.

2. Data guaranteed by design.

3. Data based on characterization results, not tested in production

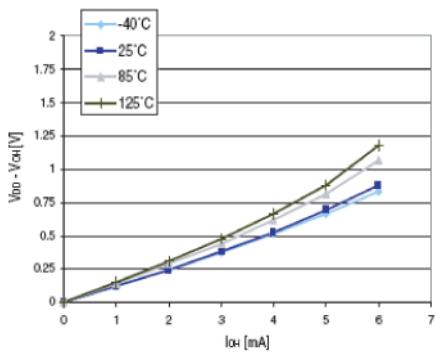
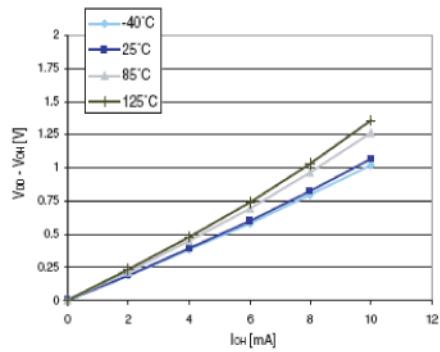
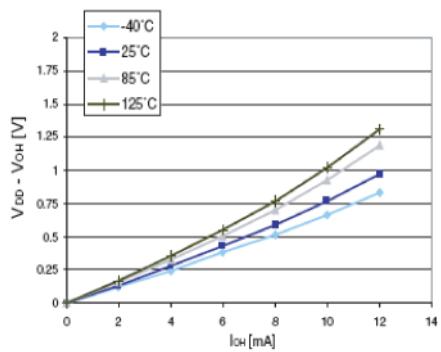
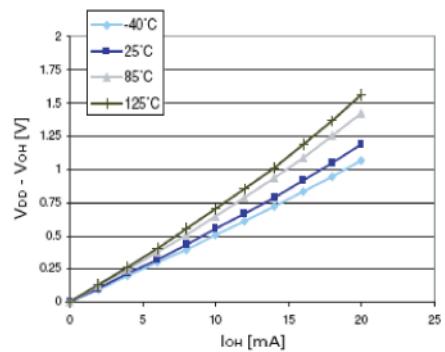
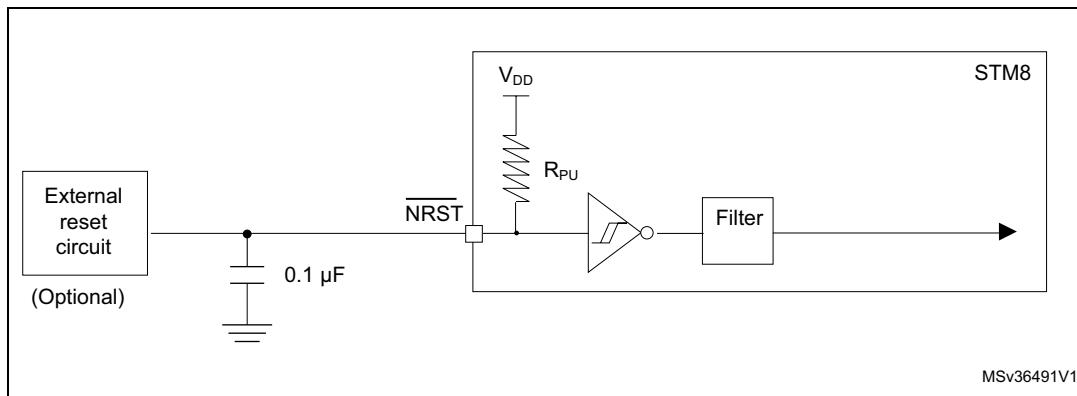
**Figure 33. Typ. $V_{DD} - V_{OH}$ @ $V_{DD} = 3.3$ V
(standard ports)****Figure 34. Typ. $V_{DD} - V_{OH}$ @ $V_{DD} = 5.0$ V
(standard ports)****Figure 35. Typ. $V_{DD} - V_{OH}$ @ $V_{DD} = 3.3$ V (high sink ports)****Figure 36. Typ. $V_{DD} - V_{OH}$ @ $V_{DD} = 5.0$ V (high sink ports)**

Figure 40. Recommended reset pin protection



MSv36491V1

10.3.9 SPI serial peripheral interface

Unless otherwise specified, the parameters given in [Table 42](#) are derived from tests performed under ambient temperature, f_{MASTER} frequency and V_{DD} supply voltage conditions. t_{MASTER} = 1/f_{MASTER}.

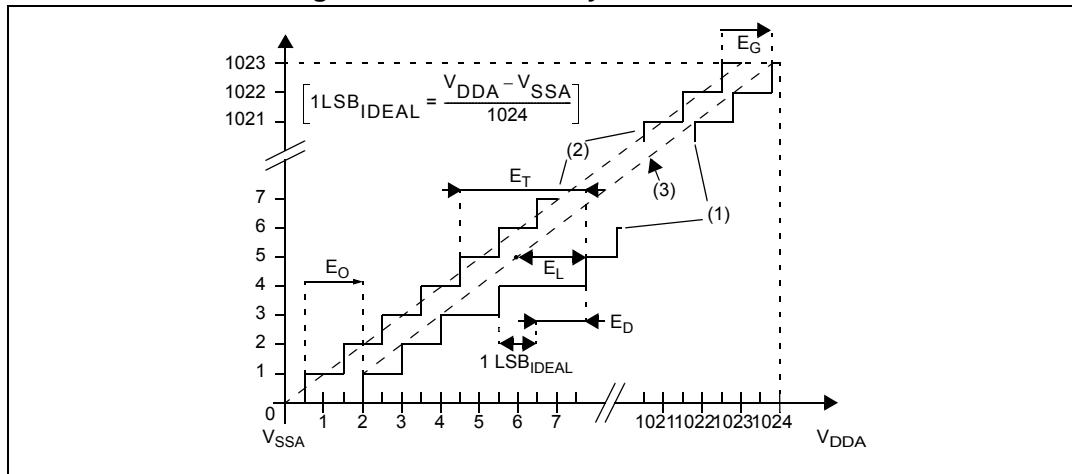
Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 42. SPI characteristics

Symbol	Parameter	Conditions ⁽¹⁾	Min	Max	Unit
f_{SCK} 1/t _{c(SCK)}	SPI clock frequency	Master mode	0	8	MHz
		Slave mode	0	6	

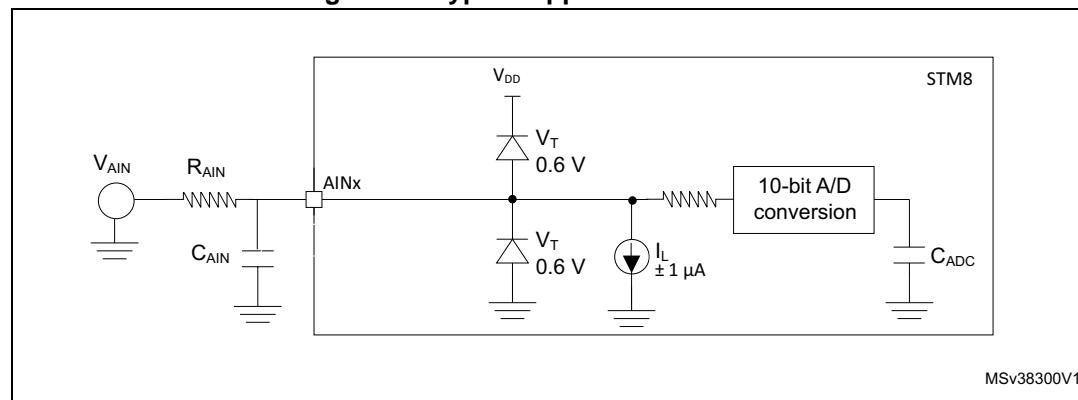
2. ADC accuracy vs. negative injection current: Injecting negative current on any of the analog input pins should be avoided as this significantly reduces the accuracy of the conversion being performed on another analog input. It is recommended to add a Schottky diode (pin to ground) to standard analog pins which may potentially inject negative current. Any positive injection current within the limits specified for $I_{INJ(PIN)}$ and $\Sigma I_{INJ(PIN)}$ in [Section 10.3.6](#) does not affect the ADC accuracy.

Figure 45. ADC accuracy characteristics



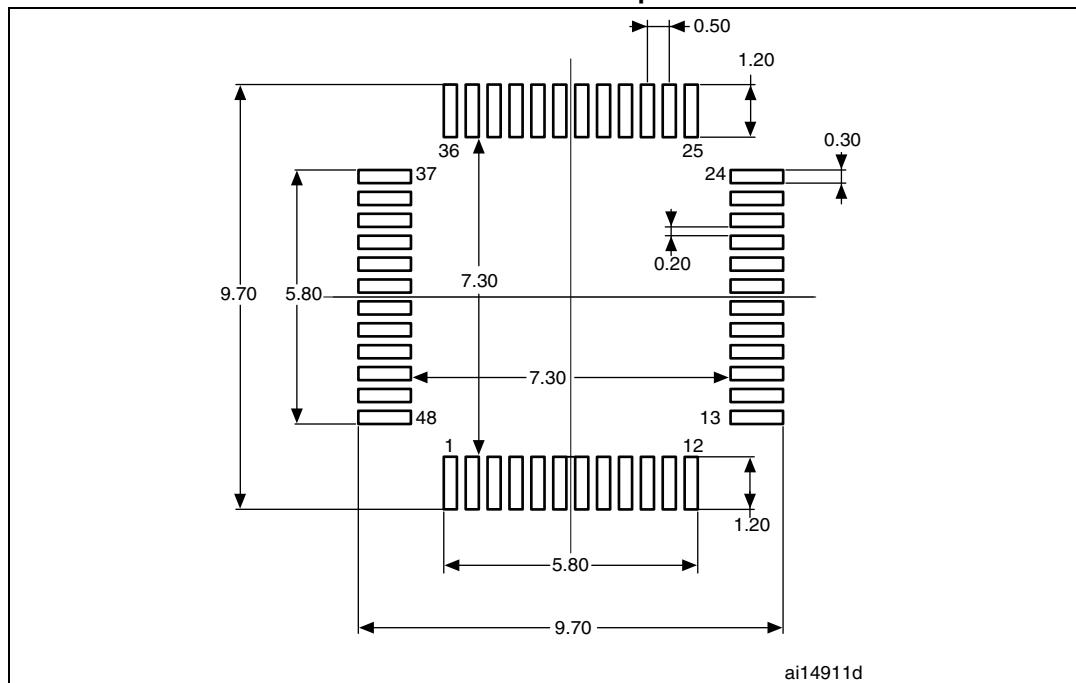
1. Example of an actual transfer curve
 2. The ideal transfer curve
 3. End point correlation line
- E_T** = Total unadjusted error: maximum deviation between the actual and the ideal transfer curves.
E_O = Offset error: deviation between the first actual transition and the first ideal one.
E_G = Gain error: deviation between the last ideal transition and the last actual one.
E_D = Differential linearity error: maximum deviation between actual steps and the ideal one.
E_L = Integral linearity error: maximum deviation between any actual transition and the end point correlation line.

Figure 46. Typical application with ADC



1. Legend: R_{AIN} = external resistance, C_{AIN} = capacitors, C_{samp} = internal sample and hold capacitor.

Figure 48. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat package recommended footprint

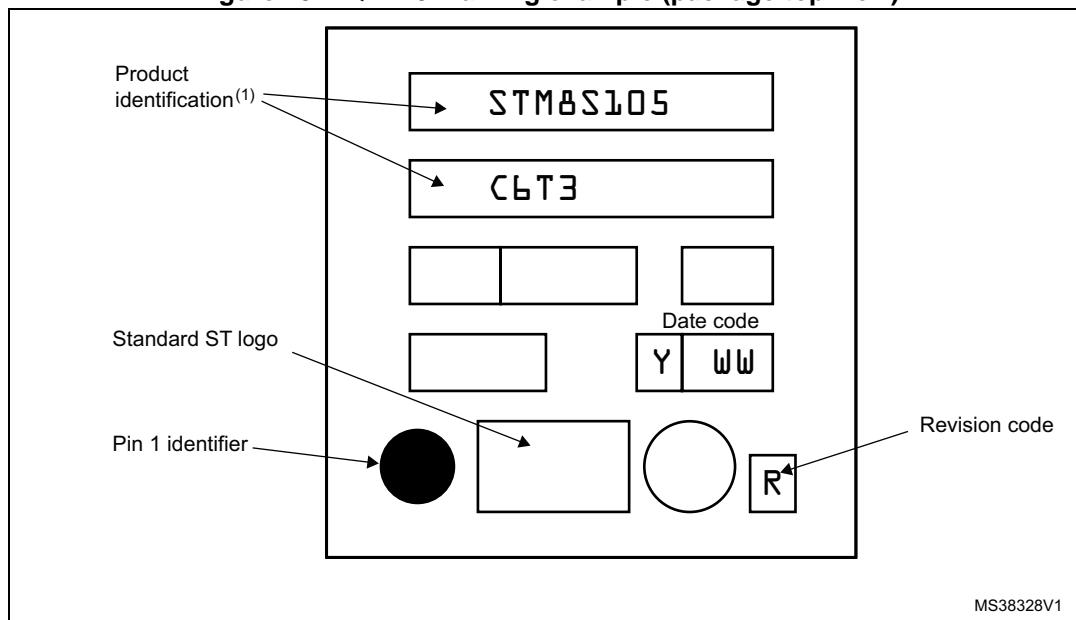


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 49. LQFP48 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such

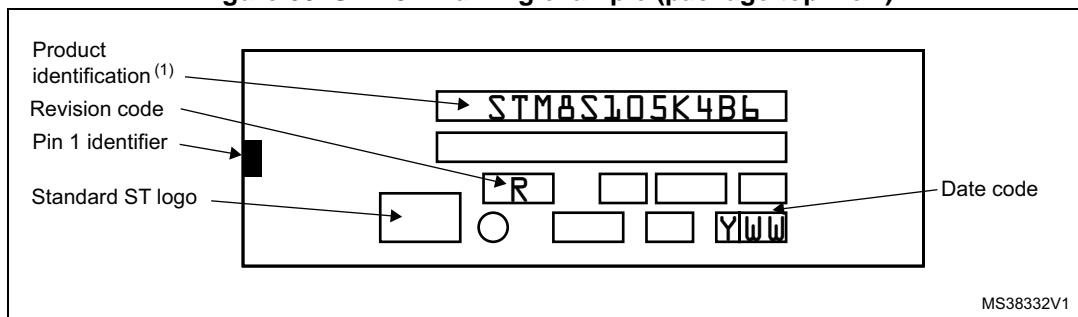
Table 55. SDIP32 package mechanical data (continued)

Dim.	mm			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
eB	-	-	12.700	-	-	0.5000
L	2.540	3.048	3.810	0.1000	0.1200	0.1500

1. Values in inches are converted from mm and rounded to 4 decimal digits

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 60. SDIP32 marking example (package top view)

1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering samples to run qualification activity.

12.2 Selecting the product temperature range

When ordering the microcontroller, the temperature range is specified in the order code (see [Section 13: Ordering information](#)).

The following example shows how to calculate the temperature range needed for a given application.

Assuming the following application conditions:

Maximum ambient temperature $T_{Amax} = 82^\circ\text{C}$ (measured according to JESD51-2),
 $I_{DDmax} = 15 \text{ mA}$, $V_{DD} = 5.5 \text{ V}$

Maximum 8 standard I/Os used at the same time in output at low level with

$I_{OL} = 10 \text{ mA}$, $V_{OL} = 2 \text{ V}$

Maximum 4 high sink I/Os used at the same time in output at low level with

$I_{OL} = 20 \text{ mA}$, $V_{OL} = 1.5 \text{ V}$

Maximum 2 true open drain I/Os used at the same time in output at low level with

$I_{OL} = 20 \text{ mA}$, $V_{OL} = 2 \text{ V}$

$P_{INTmax} = 15 \text{ mA} \times 5.5 \text{ V} = 82.5 \text{ mW}$

$P_{IOmax} = (10 \text{ mA} \times 2 \text{ V} \times 8) + (20 \text{ mA} \times 2 \text{ V} \times 2) + (20 \text{ mA} \times 1.5 \text{ V} \times 4) = 360 \text{ mW}$

This gives: $P_{INTmax} = 82.5 \text{ mW}$ and $P_{IOmax} = 360 \text{ mW}$:

$P_{Dmax} = 82.5 \text{ mW} + 360 \text{ mW}$

Thus: $P_{Dmax} = 443 \text{ mW}$.

Using the values obtained in [Table 56: Thermal characteristics](#) T_{Jmax} is calculated as follows:

For LQFP32 60°C/W

$$T_{Jmax} = 82^\circ\text{C} + (60^\circ\text{C}/\text{W} \times 443 \text{ mW}) = 82^\circ\text{C} + 27^\circ\text{C} = 109^\circ\text{C}$$

This is within the range of the suffix 6 version parts ($-40 < T_J < 131^\circ\text{C}$).

Parts must be ordered at least with the temperature range suffix 3.